SINGAPORE LABORATORY ACCREDITATION SCHEME



Number : LA-2002-0265-C-3

Date of Issue : 11 November 2022

Date of Expiry : 10 November 2026

Certificate of Accreditation

This certifies that

Cairnhill Metrology (Phils) Inc Unit 7-10, 8F Paz Madrigal Plaza, Lot-1 Finance St., Corner Industry St., Madrigal Business Park Ayala Alabang, Muntinlupa City

1780 Philippines is accredited by the Singapore Accreditation Council to

ISO / IEC 17025 : 2017

for specific scope within the field of

Calibration & Measurement

as detailed in the attached schedule.

Chairman

This Certificate is awarded subject to the organisation's compliance with the stated criteria and terms and conditions laid down by the Singapore Accreditation Council.

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SINGAPORE LABORATORY ACCREDITATION SCHEME





Cairnhill Metrology (Phils) Inc. Unit 7-10 8F, Paz Madrigal Plaza, Lot-1 Finance St. Corner Industry St., Madrigal Business Park Ayala Alabang, Muntinlupa City 1780 Philippines

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FIELD OF TESTING : Calibration and Measurement

MEASURED QUANTITIES / RANGE / INSTRUMENTS TO BE CALIBRATED		METHOD OF CALIBRATION / INSTRUMENTS USED	CALIBRATION & MEASUREMENT CAPABILITY (CMC *)
······································		In-house Calibration Procedure (WI 15-05, V7)	
(a)	Range : $X \le 650 \text{ mm}$ $Y \le 500 \text{ mm}$ $Z \le 450 \text{ mm}$ Resolution : 0.1 to 0.5 µm		1.5 μm
(b)	Range : $X \le 1000 \text{ mm}$ $Y \le 1500 \text{ mm}$ $Z \le 800 \text{ mm}$ Resolution : 0.1 to 0.5 µm		2.4 μm
2.	Accretech TSK Roundness Measurement Machine Probing diameter up to 450 mm <u>Feature examined</u> Roundness Parallelism	In-house Calibration Procedure (WI 15-01, V7)	0.006 μm 0.2 μm

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	MEASURED QUANTITIES / RANGE INSTRUMENT TO BE CALIBRATED	METHOD OF CALIBRATION / INSTRUMENTS USED	CALIBRATION & MEASUREMENT CAPABILITY (CMC *)
3.	Accretech TSK Contour Testing Machine Tracing Range X and Z up to 200 mm and 50 mm respectively Resolution : 0.1 to 1 μm	In-house Calibration Procedure (WI 15-02, V7)	
	<u>Feature Examined</u> Profile: Ball Diameter Step Height: Z-Axis		0.7 μm 0.7 μm
4.	Nikon Measuring Microscope Range X & Y: 300 x 200 mm Resolution : 0.1 μm	In-house Calibration Procedure (WI 15-12, V1)	1.2 μm
5,	Nikon Measuring Profile Projector Range X & Y: 200 x 150mm Resolution : 0.1 μm Magnification	In-house Calibration Procedure (WI 15-12, V1)	1.0 μm 0.1%
6.	Nikon Optical Non-Contact Coordinate Measuring Machine Range X, Y & Z: 1000 x 800 x 200 mm Resolution : 0.1 µm X & Y-axis Z-axis	In-house Calibration Procedure (WI 15-13, V1)	0.7 μm
	X-Y Squareness		0.9 μm 0.9 μm
7.	Universal Length Metroscope Zeiss Jena, OKM and EKM brands Resolution : 0.01 μm Range of Measuring Headstock: X ≤ 100 mm	In-house Calibration Procedure (WI 15-08, V7)	0.40
			0.10 µm

The SAC Programme is managed by Enterprise Singapore 230 Victoria Street, #09-00 Bugis Junction Office Tower, Singapore 188024 Tel: +65 6278 6666 Fax: +65 6659 0640 www.sac-accreditation.gov.sg

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	MEASURED QUANTITIES / RANGE NSTRUMENT TO BE CALIBRATED	METHOD OF CALIBRATION / INSTRUMENTS USED	CALIBRATION & MEASUREMENT CAPABILITY (CMC *)
8.	Accretech TSK Surface Roughness Testing Machine (Contact Type) Measuring Range : 80 μm Resolution : 0.001 μm Roughness, Ra	In-house Calibration Procedure (WI 15-03, V7)	0.06 μm
9 (#)	Portable Co-ordinate Measuring Machine (Hexagon Absolute RA7 and older) Resolution : 1 μm	In-house Calibration Procedure (WI 15-06, V1) ASME B89.4.22-2004 (R2014)	
(a)	Error Indication of Single Point Articulated Test (SPAT) is determined using Steel Trihedral Length Bar		5 μm
(b)	 Error indication of Volumetric Performance Test is determined using Steel Trihedral Length bar: 1. 185, 390, 580 and 800 mm 2. 220, 410, 610, 805, 1005 and 1200 mm 		5 μm
10 (#)	Portable Co-ordinate Measuring Machine (Hexagon Absolute RA8 and newer) Resolution : 1 μm	In-house Calibration Procedure (WI 15-18, V1) ISO 10360-12 V2016	
(a)	Length measurement error, E _{UNI} , is determined using Silicon Ceramic Cone Bar with the following location: 187, 387, 587, 787, 987, 1187, 1387, 1587, 1787, 1987, 2187, 2387, 2587, 2787 and 2974 mm		5.0 + (0.0050 * L) μm (L in mm)

* CMC is expressed as an expanded uncertainty estimated at a level of confidence of approximately 95 %.

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The calibration is performed at the in-house facility of Cairnhill Metrology (Phils) Inc. located at: Unit 6, GF, Paz Madrigal Plaza, Lot-1 Finance St. Corner Industry St., Madrigal Business Park, Ayala Alabang, Muntinlupa City, 1780 Philippines.

Mr Lim Chen Kee	For all accredited items
Mr Loh Kum Seng	For items 1 to 9 only
Mr Lim Seng Hoo	For items 1 to 8 only
Mr Louie B. Eustaquio	For items 2, 3 & 8 only

Note :

This laboratory is accredited in accordance with the recognised International Standard ISO/IEC 17025. A laboratory's fulfilment of the requirements of ISO/IEC 17025 means the laboratory meets both the technical competence requirements and **management system requirements** that are necessary for it to consistently deliver technically valid calibration The **management system requirements** in ISO/IEC 17025 are written in language relevant to laboratory operations and operate generally in accordance with the principles of ISO 9001.